

1071 TESCAN Lyra3 SEM

Safety instructions and Troubleshooting

Basics

- Never use the microscope including (FIB, GIS, EDX) if you are not allowed to.
- Never open the housing with the electronics or manipulate with the instrument parts (e.g. detectors, cables).

Safe Sample Loading Procedure

- Always wear gloves!
- Your samples should be cleaned prior to loading them to SEM chamber. Think of possible contamination!
- Blow your samples by nitrogen or dry air especially in the case of powder samples.
- Make sure that sample is fixed to the specimen stub/holder (turn it upside down) and that stub/holder is tightened to the SEM stage properly (but not overtightened).

Safe Stage Movements

- Check that you are in perfect focus by using degauss function (image should stay in focus after that) before moving at large distances via WD&Z function. There is a collision risk with SEM/FIB objective or GIS nozzles!
- Place the cursor over Stop button and watch Chamber View when the stage is moving. Hit the Stop button immediately when it seems there might be a collision!
- Rotate and tilt before approaching to SEM objective. If you are very close to objective, move down with the stage and then rotate or tilt it.
- When you are tilting a large sample, make sure that the outer limb of your sample is flat to avoid collision with SEM (see the scheme)
- Check if the "Keep view field" function is active the stage movement is different with and without this function!
- The touch alarm doesn't work if the sample is nonconductive!

No SEM Image

- Check that Electron beam is ON.
- Check that you have appropriate detector chosen (SE detector is recommended in the beginning).
- Go to minimum magnification.
- Use the Auto Brightness/Contrast function.
- Check that electron emission is not zero (see Electron beam panel) in such a case call the guarantee immediately.

No FIB Image

- Check that (ion) Emission is ON.
- Check the ion beam current.
- Set the minimum magnification and Auto Brightness/Contrast function.
- Set the Rough milling preset and check the ion beam current. Current should be around 10 nA, if current is significantly lower check the value of extractor voltage in FIB monitor panel. In case the extractor voltage is close to 9 kV contact guarantee.

Instrument guarantee: Eva Kolíbalová, e-mail: <u>eva.kolibalova@ceitec.vutbr.cz</u>, phone: 603 971 391 Head of CEITEC Nano: Michal Urbánek, e-mail: <u>michal.urbanek@ceitec.vutbr.cz</u>, phone: 732 781 814 Please use *the local phone line for support calls*.





1071 TESCAN Lyra3 SEM

Safety instructions and Troubleshooting

EBL

• In case you are exposing/depositing just squares instead of your pattern check in Beam Blanker panel that Electromagnetic blanker is on (GUN button is blue and "blank after scanning stops" is ticked – if not call the guarantee) and that Electrostatic blanker control is put to "Enable beam on acquisition".

RBSE Detector

- Don't move with RBSE detector to working position if the WD&Z (after focusing) is smaller than 9 mm. In Chamber view check the mutual position of the end of the detector and the stage with the samples during the detector movement.
- When finished, put the RBSE to home position.

EBIC

• Your sample should be isolated from stage. See EBIC manual or help.

Plasma Cleaner

- In case you would like to clean chamber using plasma cleaner make sure that EDX is in parking position. Using plasma cleaner when EDX is inserted may cause fatal damage to detector!
- Move with the stage to Home position before start of the cleaning.
- Consider if you can leave your samples on the stage during the cleaning.

GIS

- Check the position of the stage (WD&Z, tilt) WD ~9mm, 55° for FIBID, WD ~10 mm (sample has to be flat!), 0° for EBID; then move with GIS nozzles to working position. Watch Chamber View when GIS nozzles are moving. Hit the Stop button immediately when it seems there might be a collision!
- Don't start GIS calibration procedure if the stage is close to SEM objective (move with the stage to Home position first).
- Before first opening of the gas valve, put the electron beam off (BEAM ON button should be gray) and ion emission off (Emission button should be gray). Watch chamber pressure indicator bar and in case there is strong pressure increase (red color), wait for pumping down to green area. Then close GIS valve and open it again. If the pressure is in red area yet again, do the outgas procedure. Rapid chamber pressure increase can switch off the electron emission and there is a strong risk for cathode damage!
- In case you not see any deposition/enhanced etching check your project parameters and position of GIS nozzles. The deposition will not start if the chamber is pumped for a short time (wait minimally 30 minutes for suitable chamber pressure).

EDX

- Move EDX detector to working position carefully not to displace the fixation segment. In Chamber view check the mutual position of the end of the detector and the stage with the samples during the detector movement!
- When finished, put the EDX to standby mode (within Esprit software) and close Esprit software.

Notes

• If there is a serious problem, always contact the guarantee. Send the mail about it to other experienced users and make a note to the instrument book.

Instrument guarantee: Eva Kolíbalová, e-mail: <u>eva.kolibalova@ceitec.vutbr.cz</u>, phone: 603 971 391 Head of CEITEC Nano: Michal Urbánek, e-mail: <u>michal.urbanek@ceitec.vutbr.cz</u>, phone: 732 781 814 Please use *the local phone line for support calls*.